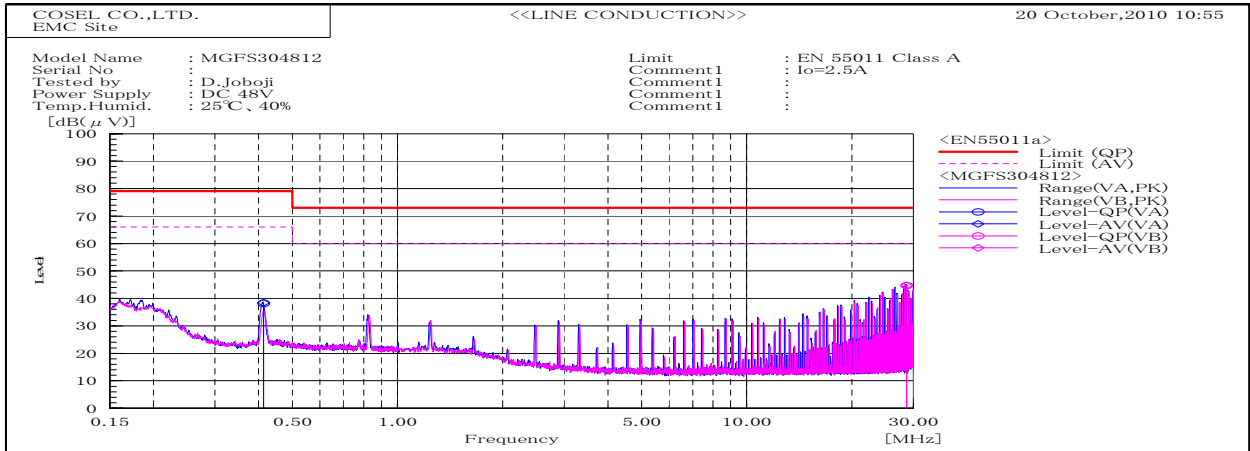
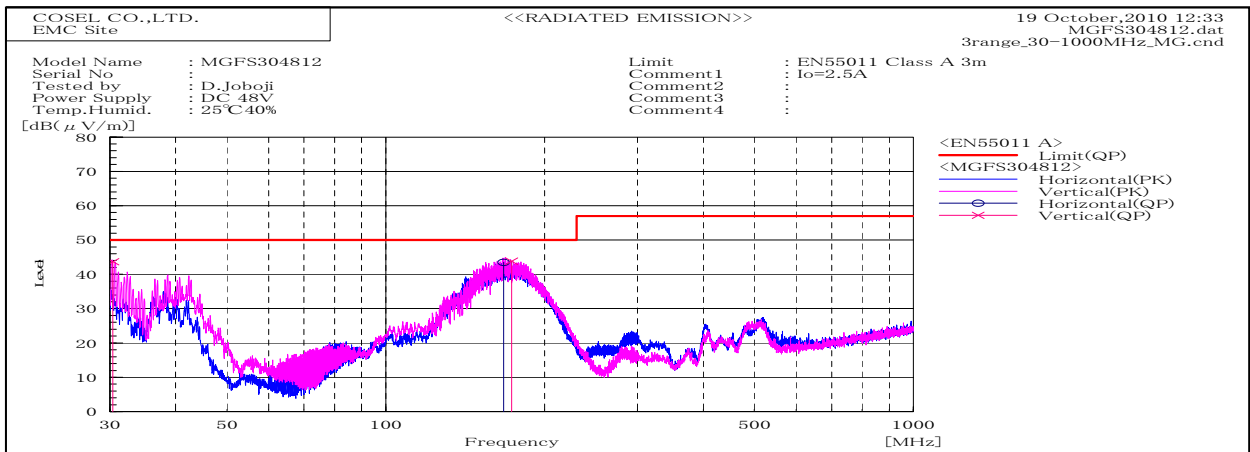


DATA SHEET		Date	20-Oct-10
Model	MGFS304812	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.41343		VA	28.1	28.3	10.1	38.2	38.4	79	66	40.8	27.6	Pass	
28.70215		VB	33.7	33.7	11	44.7	44.7	73	60	28.3	15.3	Pass	

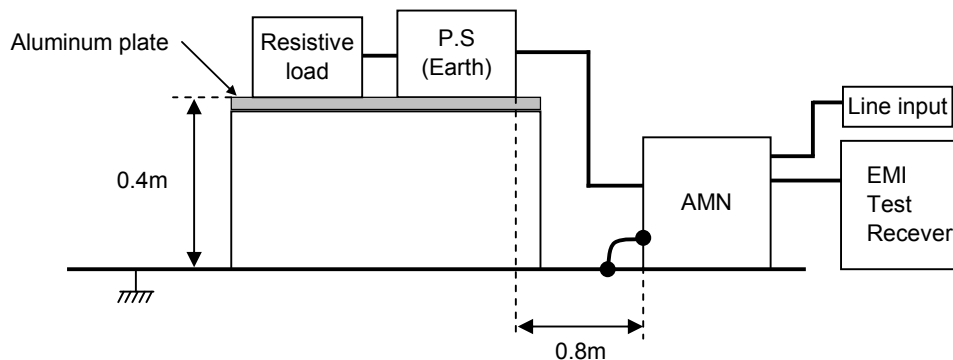


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.412	V	Stable	57.3	-13.6		43.7		50	6.3	Pass	102	42
167.255	H	Stable	65.2	-21.7		43.5		50	6.5	Pass	152	0
173.242	V	Stable	66	-22.2		43.8		50	6.2	Pass	146	258

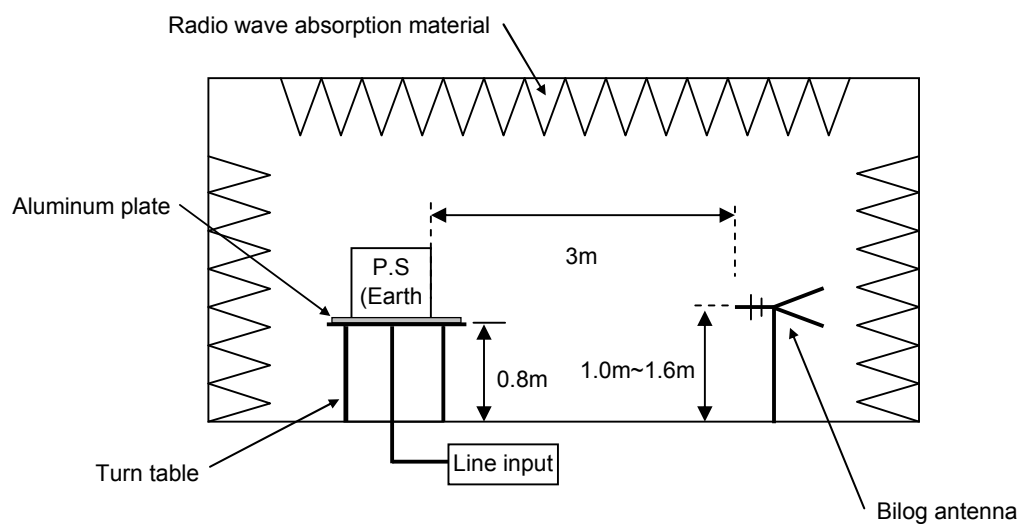
## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission



## Conditions

Test : EMI  
 Model Name : MGFS3048□□/MGFW3048□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

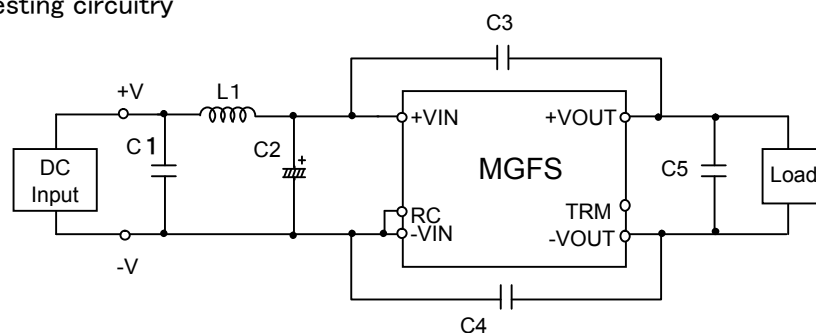


Fig.1 Testing circuitry 1

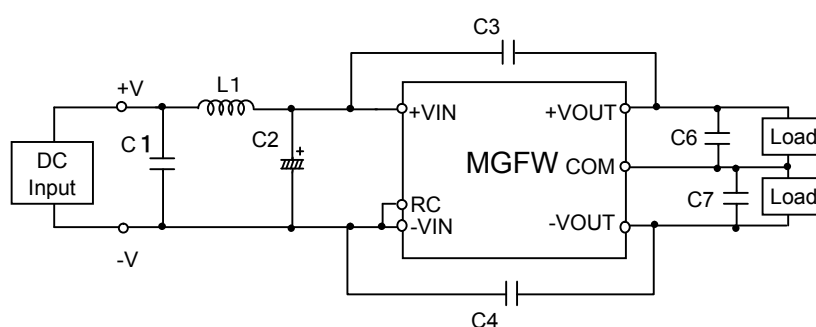


Fig.2 Testing circuitry 2

L1	: 4.7uH	CI8C-4R7	(KORIN ELECTRONICS)
C1	: 100V	2.2 $\mu$ F	Ceramic Capacitor
C2	: 80V	47 $\mu$ F	Electrolytic Capacitor
C3,C4	: 2kV	1000pF	Ceramic Capacitor
C5,C6,C7	: 25V	22 $\mu$ F	Ceramic Capacitor